

🧲 Shenzhen Zhongjian Nanfang Testing Co., Ltd.

Report No: CCISE180802102

FCC REPORT

Applicant: Baicells Technologies Co., Ltd.

Address of Applicant: 3F, Hui Yuan Development Building, No.1 Shangdi Information

Industry Base, Haidian Dist., Beijing, China

Equipment Under Test (EUT)

Product Name: mobile wifi

Model No.: R700

FCC ID: 2AG32R700A

Applicable standards: FCC CFR Title 47 Part 2

FCC CFR Title 47 Part 27 Subpart M

Date of sample receipt: 07 Aug., 2018

Date of Test: 07 Aug., to 22 Aug., 2018

Date of report issued: 23 Aug., 2018

Test Result: PASS*

*In the configuration tested, the EUT complied with the standards specified above.

Authorized Signature:



Bruce Zhang Laboratory Manager

This report details the results of the testing carried out on one sample. The results contained in this test report do not relate to other samples of the same product and does not permit the use of the CCIS product certification mark. The manufacturer should ensure that all products in series production are in conformity with the product sample detailed in this report.

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2. Version

Version No.	Date	Description
00	23 Aug., 2018	Original

Tested by: Query (hen Date: 23 Aug., 2018

Test Engineer

Reviewed by: Date: 23 Aug., 2018

Project Engineer



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4. Test Summary

Test Items	Section in CFR 47	Result			
RF Exposure (SAR)	Part 1.1307	Passed			
KF Exposure (SAK)	Part 2.1093	(Please refer to SAR Report)			
RF Output Power	Part 2.1046	Pass			
Ki Output rowei	Part 27.50 (h)(2)	F 055			
Peak-to-Average Ratio	Part 27.50(d)(5)	Pass			
Modulation Characteristics	Part 2.1047	Pass			
000/ 9 26 dD Occupied Bondwidth	Part 2.1049	Dees			
99% & -26 dB Occupied Bandwidth	Part 27.53(m)	Pass			
Spurious Emissions at Antenna Terminal	Part 2.1051	Pass			
Spurious Emissions at Antenna Terminal	Part 27.53(m)	F 455			
Field Strength of Spurious Radiation	Part 2.1053	Pass			
Tield Streffgtif of Spurious (Kadiation)	Part 27.53(m)	F 055			
Out of band emission, Band Edge	Part 22.917(a)	Pass			
Out of band emission, band Edge	Part 27.53(m)	r ass			
Frequency stability vs. temperature	Part 27.54	Pass			
r requerity stability vs. temperature	Part 2.1055(a)(1)(b)	1 833			
Frequency stability vs. voltage	Part 27.54	Pass			
r requeries stability vs. voltage	Part 2.1055(d)(2)	1 455			
Pass: The EUT complies with the essential requirements in the standard.					



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5. General Information

5.1 Client Information

Applicant:	Baicells Technologies Co., Ltd.
Address:	3F, Hui Yuan Development Building, No.1 Shangdi Information Industry Base, Haidian Dist., Beijing, China
Manufacturer:	Baicells Technologies Co., Ltd.
Address:	3F, Hui Yuan Development Building, No.1 Shangdi Information Industry Base, Haidian Dist., Beijing, China

5.2 General Description of E.U.T.

Product Name:	mobile wifi
Model No.:	R700
Operation Frequency range:	LTE Band 41: 2496MHz~2690MHz
Modulation type:	QPSK, 16QAM
Antenna type:	Internal Antenna
Antenna gain:	LTE Band 41: 1.0 dBi
Power supply:	Rechargeable Li-ion Battery DC3.7V-2000mAh
AC adapter :	Model: TPA-5950100UU Input: AC100-240V, 50/60Hz, 0.2A Output: DC 5.0V, 1A





Test Channel:

LTE	Band 41 (5Mh	Hz)	LTE Band 41 (10MHz)				
Channel		Frequency (MHz)	Channel		Frequency (MHz)		
Lowest channel	39675	2498.5	Lowest channel	39700	2501.0		
Middle channel	40620	2593.0	Middle channel	40620	2593.0		
Highest channel 41565		2687.5	Highest channel 41540		2685.0		
LTE	Band 41 (15M	Hz)	LTE Band 41 (20MHz)				
Channe	el	Frequency (MHz)	Channel Frequency (MHz				
Lowest channel	39725	2503.5	Lowest channel	39750	2506.0		
Middle channel	40620	2593.0	Middle channel	40620	2593.0		
Highest channel 41515		2682.5	Highest channel	Highest channel 41490			



5.3 Test environment and mode

Operating Environment	Operating Environment:				
Temperature:	Normal: 15℃ ~ 35℃, Extreme: -30℃ ~ +50℃				
Humidity:	20 % ~ 75 % RH				
Atmospheric Pressure:	1008 mbar				
Voltage:	Nominal: 3.7Vdc, Extreme: Low 3.5Vdc, High 4.25Vdc				
Test mode:					
LTE QPSK mode	Keep the EUT communication with simulated station in QPSK mode				
LTE 16-QAM mode Keep the EUT communication with simulated station in 16-QAM mode					

Remark: The EUT has been tested under continuous transmitting mode. Channel Low, Mid and High for each type band with rated data rate were chosen for full testing. The field strength of spurious radiation emission was measured as EUT stand-up position (H mode) and lie down position (E1, E2 mode) for these modes with power adaptor, earphone and Data cable. Just the worst case position (H mode) shown in report.

5.4 Description of Support Units

Test Equipment	Manufacturer	Model No.	Serial No.	
Simulated Station	Simulated Station Anritsu		6201026545	

5.5 Measurement Uncertainty

Parameters	Expanded Uncertainty	
Radiated Emission (9kHz ~ 30MHz)	±2.76 dB (k=2)	
Radiated Emission (30MHz ~ 1000MHz)	±4.28 dB (k=2)	
Radiated Emission (1GHz ~ 18GHz)	±5.72 dB (k=2)	
Radiated Emission (18GHz ~ 40GHz)	±2.88 dB (k=2)	

5.6 Related Submittal(s) / Grant (s)

This is an original grant, no related submittals and grants.

5.7 Laboratory Facility

The test facility is recognized, certified, or accredited by the following organizations:

• FCC - Registration No.: 727551

Shenzhen Zhongjian Nanfang Testing Co., Ltd. has been accredited as a testing laboratory by FCC (Federal Communications Commission). The Registration No. is 727551.

• IC - Registration No.: 10106A-1

The 3m Semi-anechoic chamber of Shenzhen Zhongjian Nanfang Testing Co., Ltd. has been Registered by Certification and Engineering Bureau of Industry Canada for radio equipment testing with Registration No.: 10106A-1.

CNAS - Registration No.: CNAS L6048

Shenzhen Zhongjian Nanfang Testing Co., Ltd. is accredited to ISO/IEC 17025:2005 General Requirements for the Competence of Testing and Calibration laboratories for the competence of testing. The Registration No. is CNAS L6048.

A2LA - Registration No.: 4346.01

This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2005 General requirements for the competence of testing and calibration laboratories. The test scope can be found as below link: https://portal.a2la.org/scopepdf/4346-01.pdf

Shenzhen Zhongjian Nanfang Testing Co., Ltd.
No. B-C, 1/F., Building 2, Laodong No.2 Industrial Park, Xixiang Road, Bao'an District, Shenzhen, Guangdong, China
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5.8 Laboratory Location

Shenzhen Zhongjian Nanfang Testing Co., Ltd.

Address: No. B-C, 1/F., Building 2, Laodong No.2 Industrial Park, Xixiang Road,

Bao'an District, Shenzhen, Guangdong, China Tel: +86-755-23118282, Fax: +86-755-23116366

Email: info@ccis-cb.com, Website: http://www.ccis-cb.com

5.9 Test Instruments list

Test Equipment	Manufacturer	Model No.	Serial No.	Cal. Date (mm-dd-yy)	Cal. Due date (mm-dd-yy)
3m SAC	SAEMC	9m*6m*6m	966	07-22-2017	07-21-2020
BiConiLog Antenna	SCHWARZBECK	VULB9163	497	03-16-2018	03-15-2019
Biconical Antenna	SCHWARZBECK	VUBA9117	359	06-22-2017	06-21-2020
Horn Antenna	SCHWARZBECK	BBHA9120D	916	03-16-2018	03-15-2019
Horn Antenna	SCHWARZBECK	BBHA9120D	1805	06-22-2017	06-21-2020
EMI Test Software	AUDIX	E3	V	ersion: 6.110919	b
Pre-amplifier	HP	8447D	2944A09358	03-07-2018	03-06-2019
Pre-amplifier	CD	PAP-1G18	11804	03-07-2018	03-06-2019
Spectrum analyzer	Rohde & Schwarz	FSP30	101454	03-07-2018	03-06-2019
EMI Test Receiver	Rohde & Schwarz	ESRP7	101070	03-07-2018	03-06-2019
Spectrum Analyzer	Agilent	N9020A	MY50510123	10-29-2017	10-28- 2018
Signal Generator	Rohde & Schwarz	SMX	835454/016	03-07-2018	03-06-2019
Signal Generator	R&S	SMR20	1008100050	03-07-2018	03-06-2019
RF Switch Unit	MWRFTEST	MW200	N/A	N/A	N/A
Test Software	MWRFTEST	MTS8200		Version: 2.0.0.0	
Cable	ZDECL	Z108-NJ-NJ-81	1608458	03-07-2018	03-06-2019
Cable	MICRO-COAX	MFR64639	K10742-5	03-07-2018	03-06-2019
Cable	SUHNER	SUCOFLEX100	58193/4PE	03-07-2018	03-06-2019
DC Power Supply	XinNuoEr	WYK-10020K	1409050110020	10-31-2017	10-30-2018
Temperature Humidity Chamber	HengPu	HPGDS-500	20140828008	09-24-2017	09-23-2018
Simulated Station	Rohde & Schwarz	CMW500	140493	06-24-2018	06-23-2019



6. Test results

6.1 Conducted Output Power

Test Requirement:	Part 22.913(a)(2),Part 27.50 (h)(2)		
Test Method:	ANSI/TIA-603-D 2010		
Limit:	Mobile and other user stations. Mobile stations are limited to 2.0 watts EIRP. All user stations are limited to 2.0 watts transmitter output power.		
Test Setup:	System simulator ATT EUT		
Test Procedure:	The transmitter output was connected to a calibrated attenuator, the other end of which was connected to the CMW500. Transmitter output power was read off in dBm.		
Test Instruments:	Refer to section 5.9 for details		
Test mode:	Refer to section 5.3 for details		
Test results:	Passed		





Measurement Data:

	weasurement Data:							
	Bandwidth					Average Power (dBm)		
LTE Band	(MHz)	Modulation	RB Size	RB Offset	39675	40620	41565	
	(1011 12)				2498.5MHz	2593.0MHz	2687.5MHz	
			1	0	22.07	21.86	21.62	
			1	12	22.15	22.15	21.74	
			1	24	22.04	22.11	21.73	
		QPSK	12	0	21.30	21.24	20.84	
			12	6	21.30	21.12	20.83	
			12	11	21.29	21.02	20.66	
41	5		25	0	21.21	21.01	20.80	
41	5		1	0	21.35	20.42	20.59	
			1	12	20.53	20.46	20.46	
			1	24	20.37	20.53	20.52	
		16QAM	12	0	20.32	20.45	20.53	
			12	6	20.35	20.56	20.52	
			12	11	20.31	20.46	20.42	
			25	0	20.37	20.42	20.48	
	Bandwidth			RB Offset	Average Power (dBm)			
LTE Band	(MHz)	Modulation	RB Size		39700	40620	41540	
	(1011 12)				2501.0MHz	2593.0MHz	2685.0MHz	
			1	0	22.24	22.15	21.87	
			1	24	22.41	22.15	21.77	
			1	49	22.28	22.21	21.61	
		QPSK	25	0	21.40	21.53	20.86	
			25	12	21.51	21.29	20.83	
			25	24	21.28	21.09	20.75	
41	10		50	0	21.40	21.09	20.92	
41	10		1	0	20.74	20.31	20.82	
			1	24	20.80	20.39	20.79	
			1	49	20.58	20.41	20.78	
		16QAM	25	0	20.49	20.42	20.56	
			25	12	20.48	20.46	20.54	
			25	24	20.44	20.35	20.51	
			50	0	20.38	20.60	20.39	





	Bandwidth (MHz)	Modulation	RB Size		Average Power (dBm)		
LTE Band				RB Offset	39725	40620	41515
					2503.5MHz	2593.0MHz	2682.5MHz
		QPSK	1	0	22.01	22.07	22.08
			1	37	22.25	22.22	21.84
			1	74	22.05	22.08	21.83
			36	0	21.55	21.27	20.98
			36	16	21.49	21.15	20.88
			36	35	21.16	21.13	20.83
44	15		75	0	21.27	21.13	20.98
41		16QAM	1	0	20.77	20.68	20.65
			1	37	20.80	20.52	20.35
			1	74	20.56	20.68	20.41
			36	0	20.63	20.50	20.38
			36	16	20.43	20.36	20.31
			36	35	20.41	20.35	20.36
			75	0	20.33	20.36	20.32
	Bandwidth (MHz)	Modulation	RB Size	RB Offset	Average Power (dBm)		
LTE Band					39750	40620	41490
					2506.0MHz	2593.0MHz	2680.0MHz
	20	QPSK	1	0	22.09	22.09	22.08
			1	49	22.38	22.27	22.00
			1	99	22.08	22.17	21.65
41			50	0	21.54	21.29	21.07
			50	24	21.68	21.17	21.05
			50	49	21.19	21.14	20.90
			100	0	21.19	21.12	20.90
		16QAM	1	0	20.70	20.56	20.54
			1	49	20.89	20.68	20.55
			1	99	20.61	20.69	20.41
			50	0	20.37	20.51	20.58
			50	24	20.35	20.55	20.57
			50	49	20.43	20.58	20.54
			100	0	20.45	20.42	20.41





6.2 Peak-to-Average Ratio

Test Requirement:	Part 27.50(d)(5)
Test Method:	ANSI/TIA-603-D 2010
Limit:	The peak-to-average ratio (PAR) of the transmission may not exceed 13 dB.
Test Setup:	System simulator Splitter ATT EUT Spectrum Analyzer
Test Procedure:	 The RF output of the transceiver was connected to a spectrum analyzer through appropriate attenuation. Set the CCDF option in spectrum analyzer, RBW ≥ OBW, Set the EUT working in highest power level, measured and recorded the 0.1% as PAPR level. Repeat step 1~3 at other frequency and modulations.
Test Instruments:	Refer to section 5.9 for details
Test mode:	Refer to section 5.3 for details
Test results:	Passed





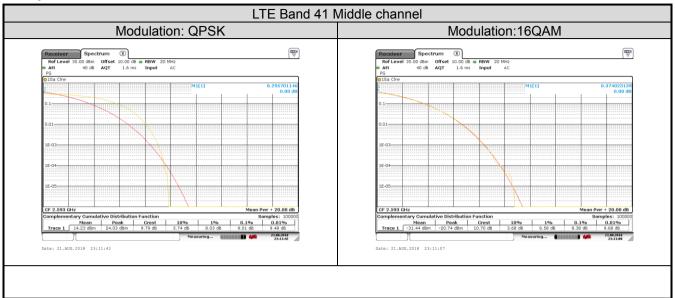
Measurement Data (Worst case):

Bandwidth	Modulation	RB Size	RB Offset	PAPR	
LTE Band 41 (Middle Channel)					
20MHz	QPSK	100	0	9.01	
	16QAM	100	0	8.38	





Test plots as below:







6.3 Occupy Bandwidth

or coupy barrantam	
Test Requirement:	Part 27.53(m)
Test Method:	ANSI/TIA-603-D 2010
Test Setup:	System simulator Spectrum Analyzer
Test Procedure:	 The EUT's output RF connector was connected with a short cable to the spectrum analyzer RBW was set to about 1% ~ 5% of emission BW, VBW= 3 times RBW. -26dBc display line was placed on the screen (or 99% bandwidth), the occupied bandwidth is the delta frequency between the two points where the display line intersects the signal trace.
Test Instruments:	Refer to section 5.9 for details
Test mode:	Refer to section 5.3 for details
Test results:	Passed





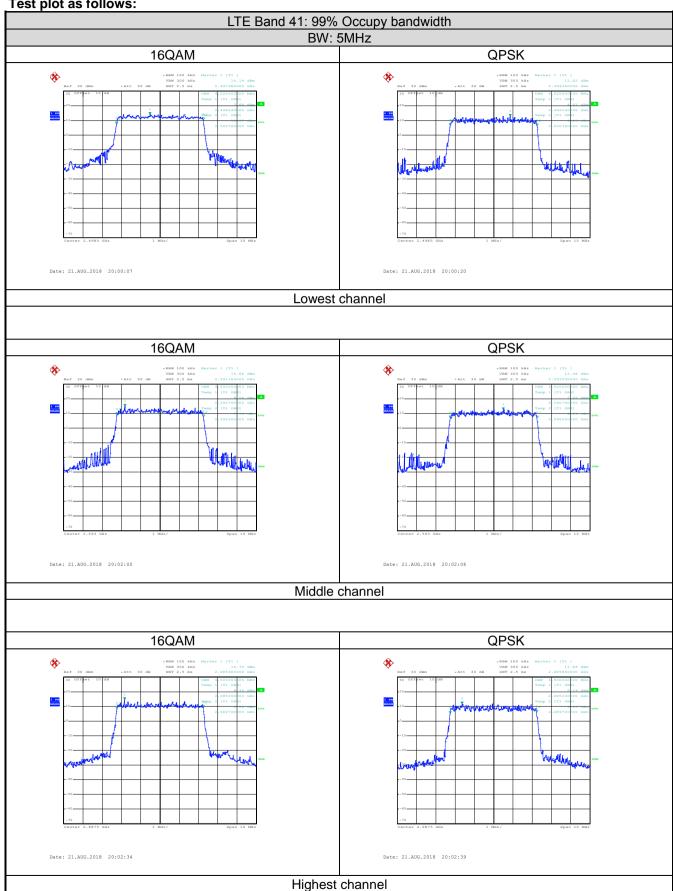
Measurement Data:

	LTE Band 41				
Bandwidth	Channel	Frequency (MHz)	Modulation	99% OBW (kHz)	-26dBcEBW (kHz)
	39675	2498.5	16QAM	4520	4960
			QPSK	4520	5000
5MHz	40620	2593.0	16QAM	4500	4960
SIVILIZ			QPSK	4520	4820
	41565	2687.5	16QAM	4500	4980
	41303		QPSK	4500	4940
	39700	0504.0	16QAM	9040	10160
		2501.0	QPSK	9120	10000
10MHz	40620	2593.0	16QAM	9040	10000
TUIVIEZ			QPSK	9040	10040
	41540	2685.0	16QAM	9040	10120
			QPSK	9040	10000
	39725	2503.5	16QAM	13500	15060
			QPSK	13500	14760
15MHz	40620	2593.0	16QAM	13500	14760
IOIVIEZ			QPSK	13500	14520
	41515	2682.5	16QAM	13500	14820
			QPSK	13500	14520
	39750	2506.0	16QAM	17920	19280
			QPSK	17920	19360
	40620	2593.0	16QAM	17920	19600
20MHz			QPSK	17920	19280
	41490	2680.0	16QAM	17920	19280
			QPSK	17920	19120



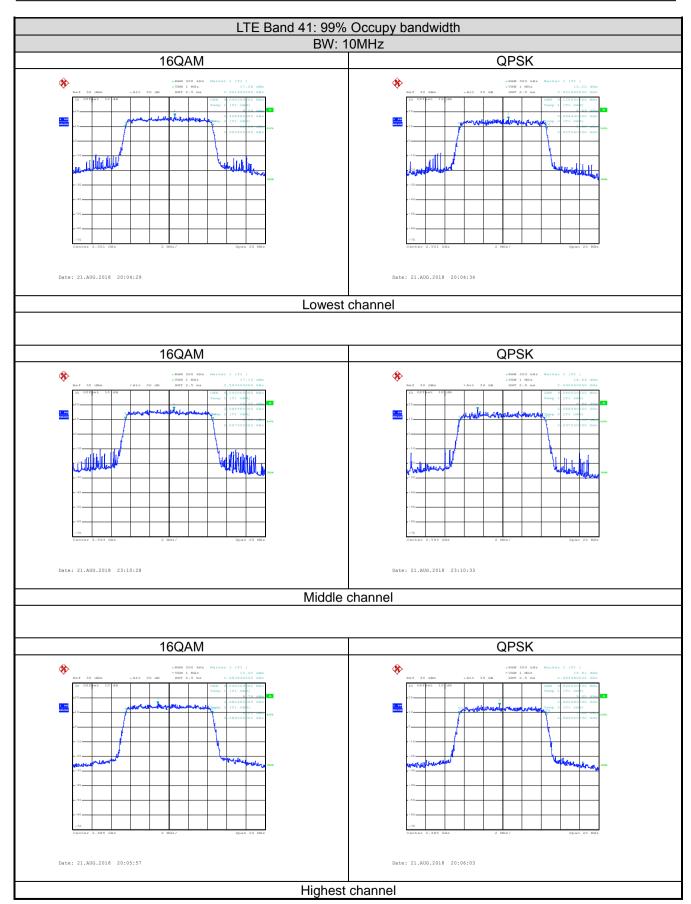


Test plot as follows:



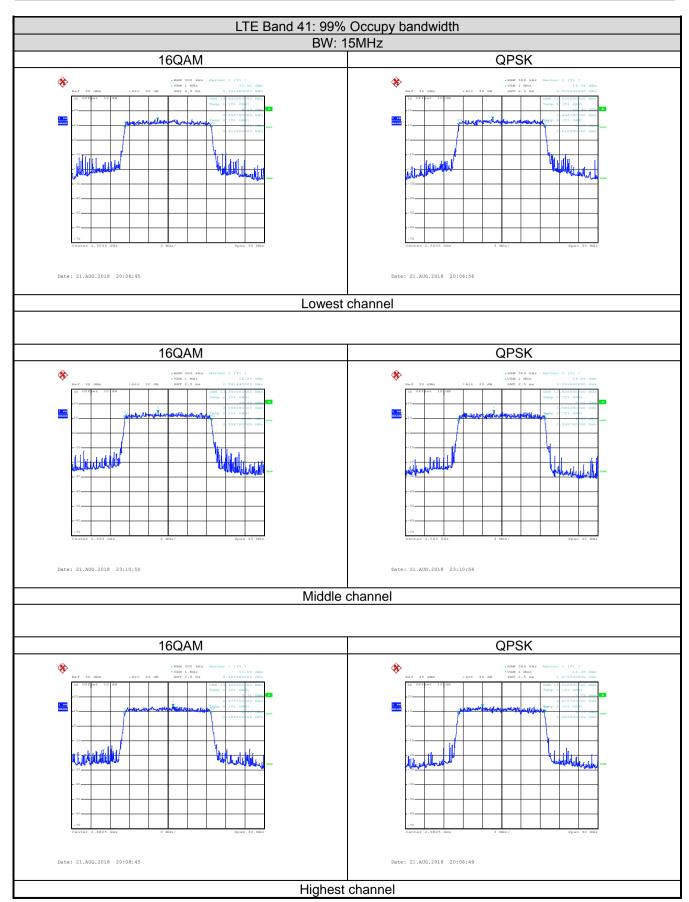






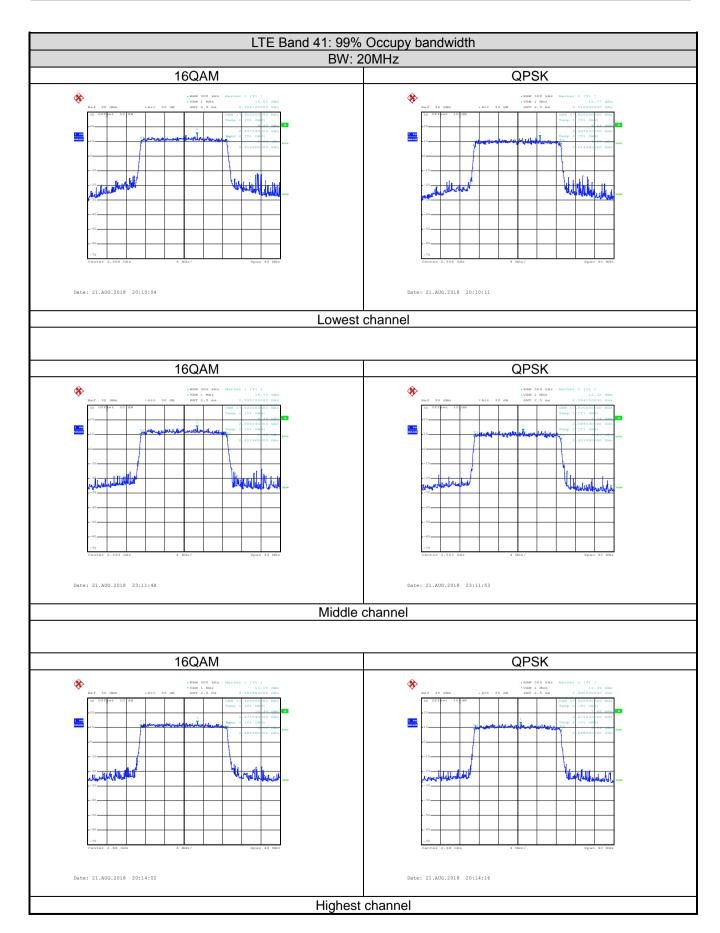














6.4 Out of band emission at antenna terminals

Test Requirement:	Part 22.917(b), Part 27.53(m)		
Test Method:	ANSI/TIA-603-D 2010		
Limit:	For mobile digital stations, the attenuation factor shall be not less than 40 + 10 log (P) dB on all frequencies between the channel edge and 5 megahertz from the channel edge, 43 + 10 log (P) dB on all frequencies between 5 megahertz and X megahertz from the channel edge, and 55 + 10 log (P) dB on all frequencies more than X megahertz from the channel edge, where X is the greater of 6 megahertz or the actual emission bandwidth as defined in paragraph (m)(6) of this section. In addition, the attenuation factor shall not be less that 43 + 10 log (P) dB on all frequencies between 2490.5 MHz and 2496 MHz and 55 + 10 log (P) dB at or below 2490.5 MHz. Mobile Satellite Service licensees operating on frequencies below 2495 MHz may also submit a documented interference complaint against BRS licensees operating on channel BRS Channel 1 on the same terms and conditions as adjacent channel BRS or EBS licensees.		
Test Setup:	System simulator Splitter ATT EUT Spectrum Analyzer		
Test Procedure:	 The RF output of the transceiver was connected to a spectrum analyzer through appropriate attenuation. The resolution bandwidth of the spectrum analyzer was set at 100 kHz when below 1GHz, 1MHz when above 1 GHz; sufficient scans were taken to show the out of band Emissions if any up to 10th harmonic. For the out of band: Set the RBW=100 kHz, VBW=300 kHz when below 1 GHz, RBW =1 MHz, VBW=3 MHz when above 1 GHz, Start=30MHz, Stop= 10th harmonic. Band Edge Requirements: In the 1 MHz bands immediately outside and adjacent to the frequency block, a resolution bandwidth of at least 1 percent of the emission bandwidth of the fundamental emission of the transmitter may be employed to measure the out of band Emissions. 		
Test Instruments:	Refer to section 5.9 for details		
Test mode:	Refer to section 5.3 for details		
Test results:	Passed		
Remark:	Pre-scan all RB Size and offset, and found the RB Size and offset of worst case, so the report shows only the worst case test data.		





Test plots as follows (Conducted spurious emission) (worst case): LTE Band 41: 16 QAM & Size 1 BW: 5MHz Lowest channel Date: 21.AUG.2018 21:32:17 Date: 21.AUG.2018 22:40:03 30MHz~1GHz 1GHz~27GHz Middle channel Date: 21.AUG.2018 21:33:06 Date: 21.AUG.2018 22:37:25 30MHz~1GHz 1GHz~27GHz High channel

Date: 21.AUG.2018 22:35:54

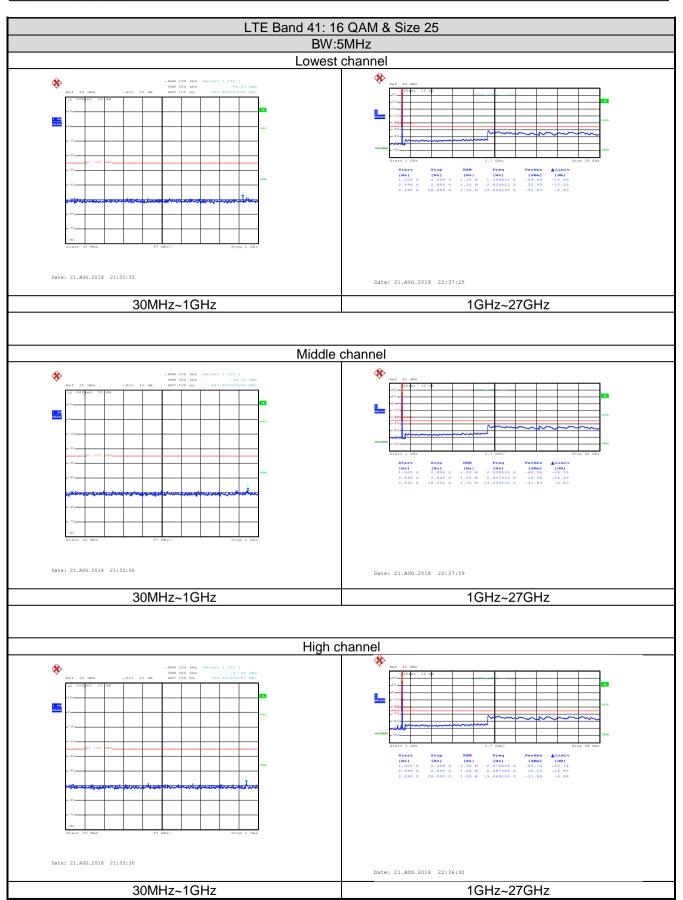
1GHz~27GHz

30MHz~1GHz

Date: 21.AUG.2018 21:33:21

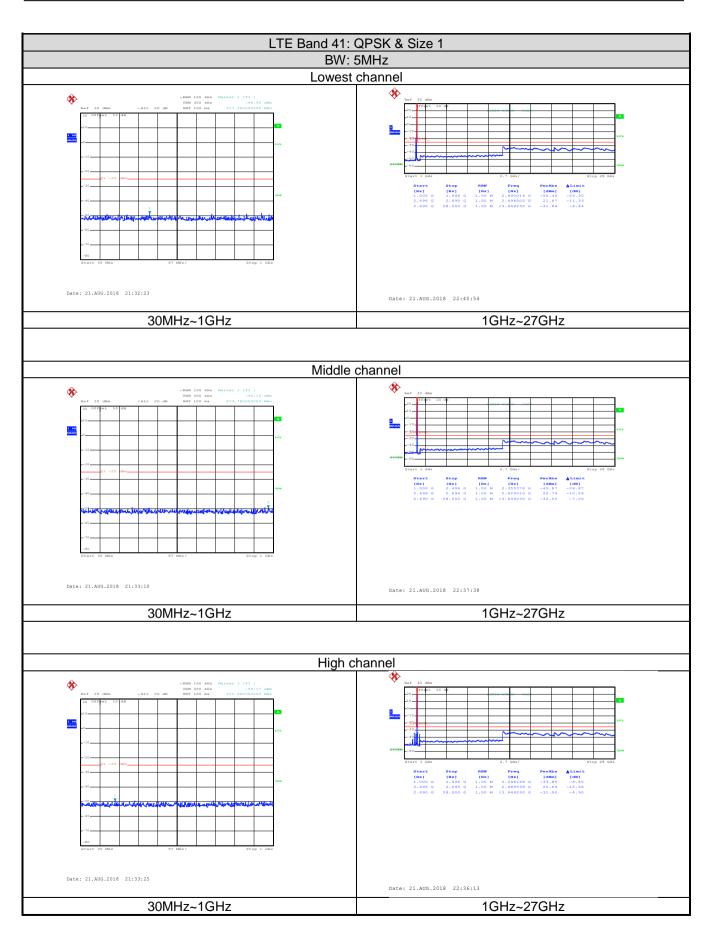






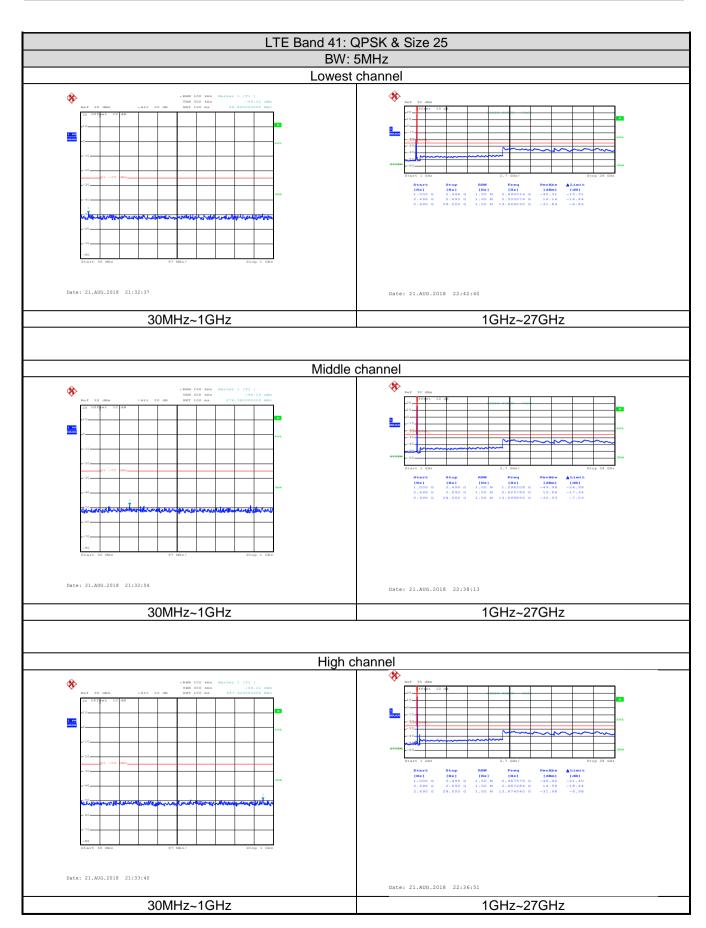






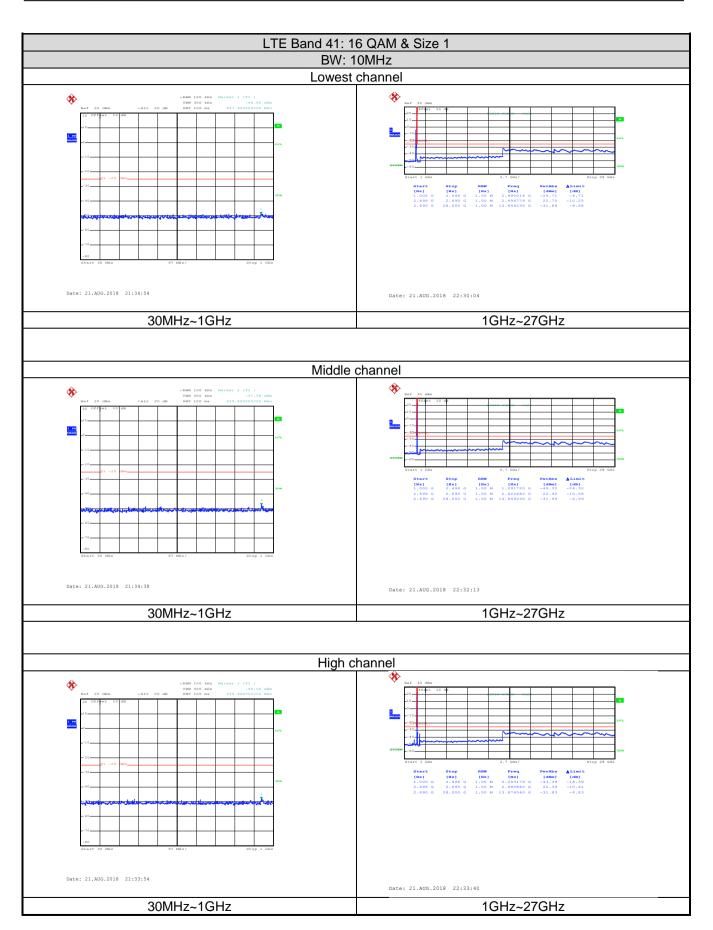






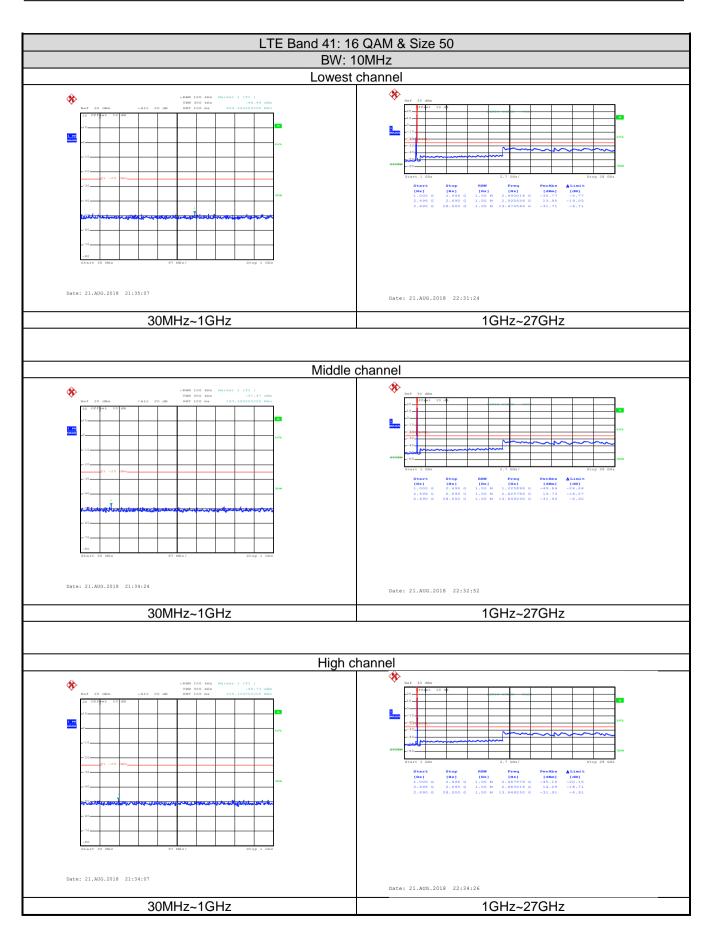






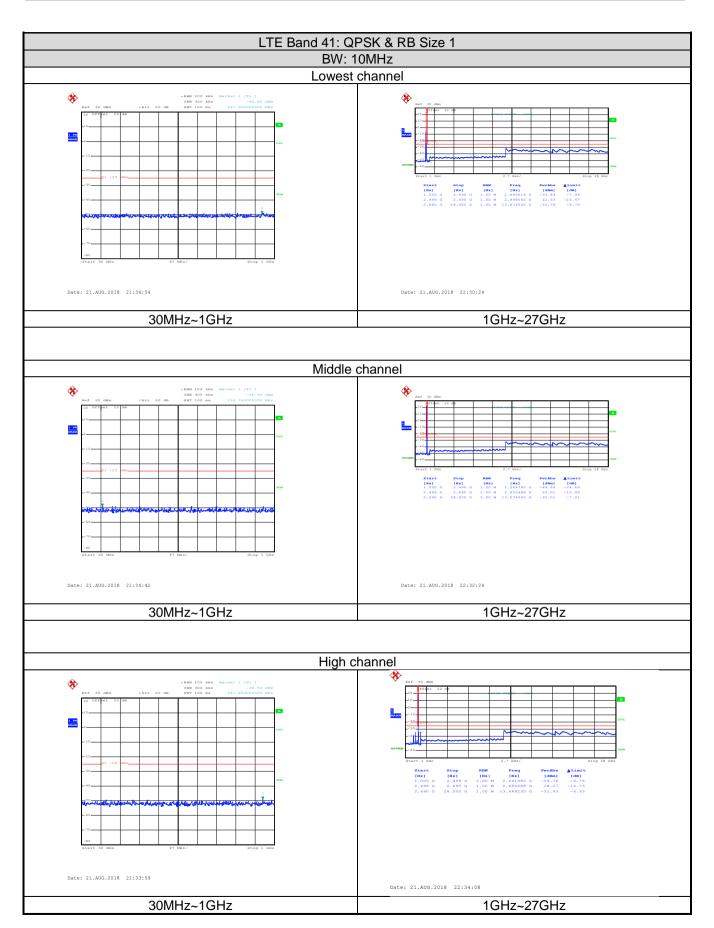






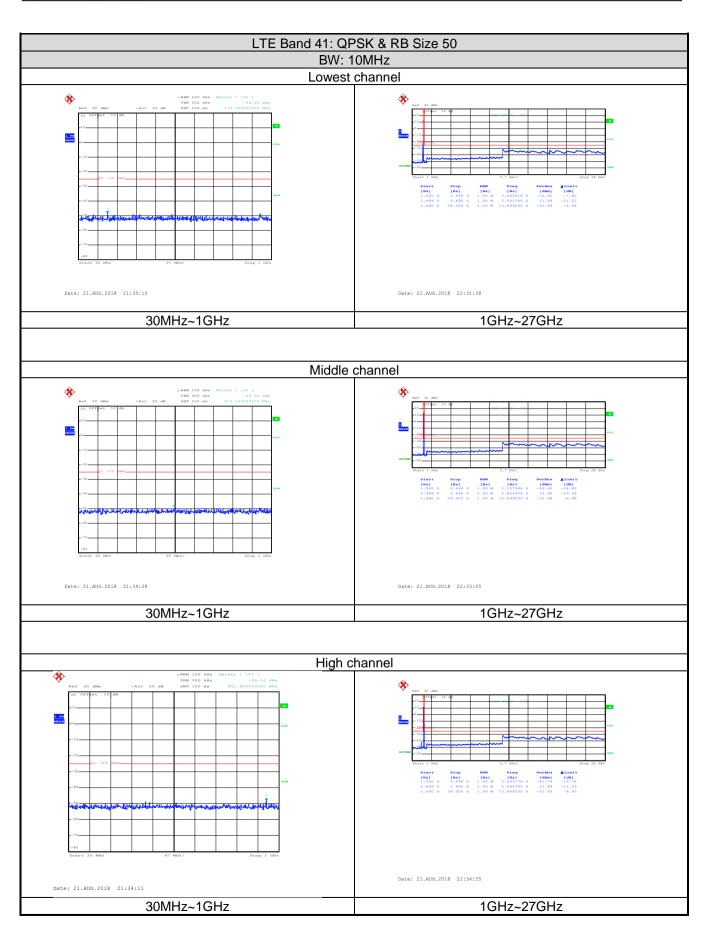






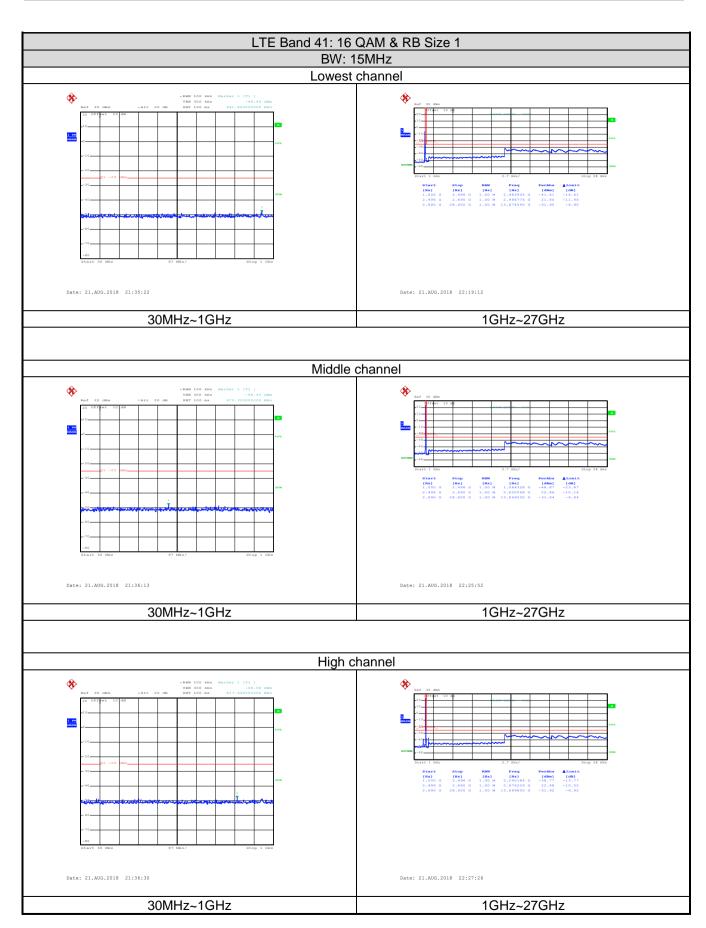






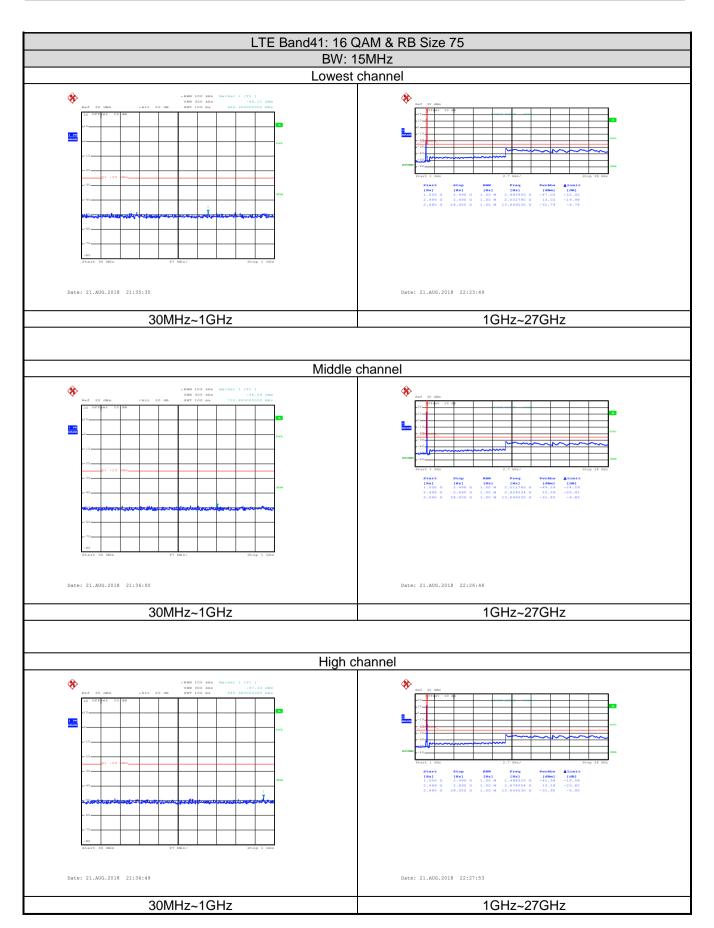






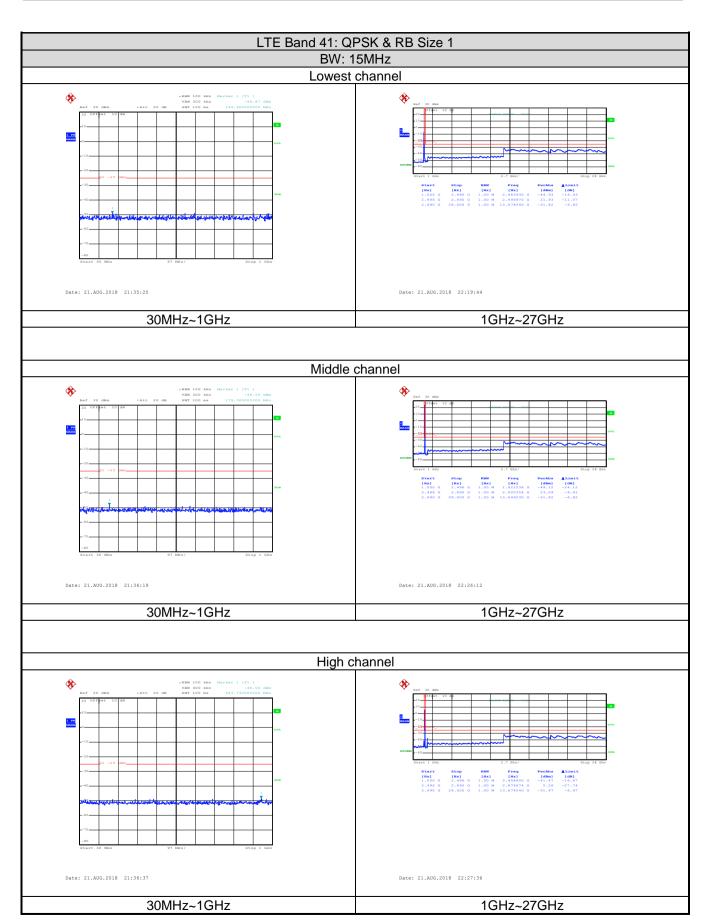






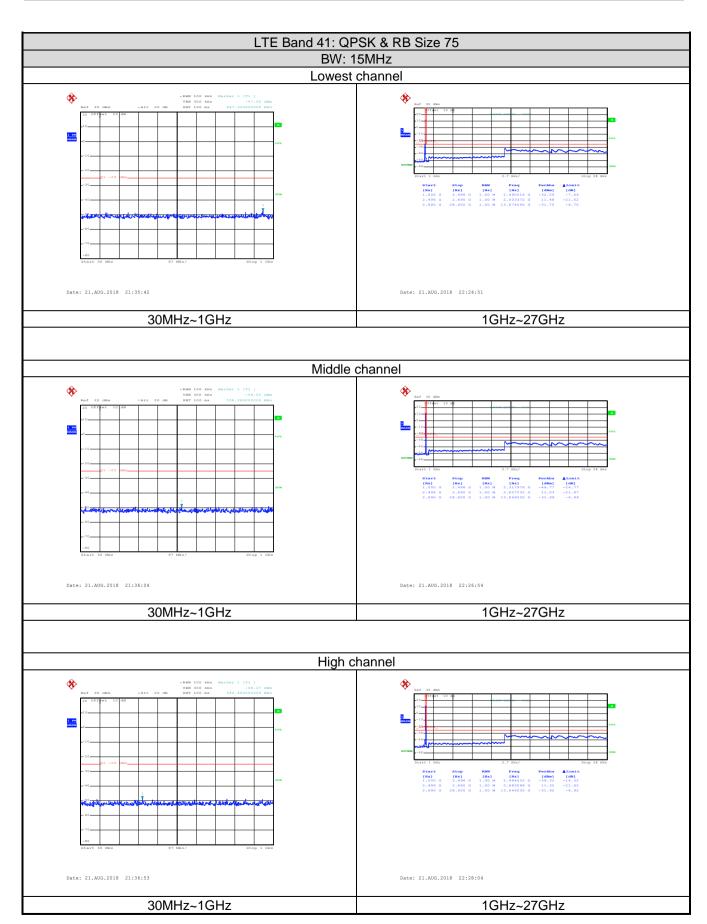






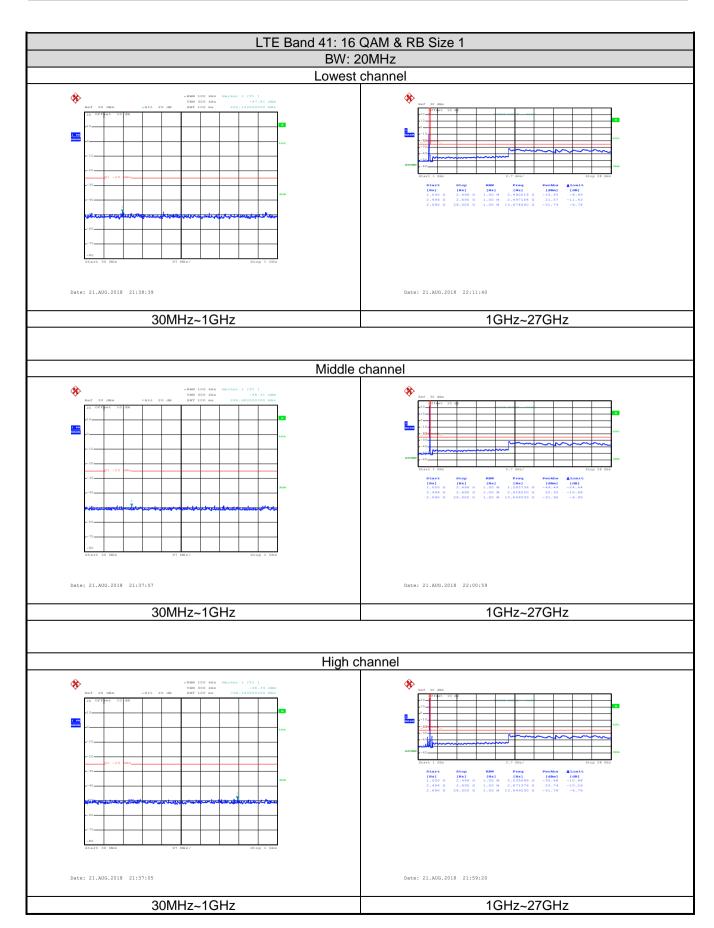






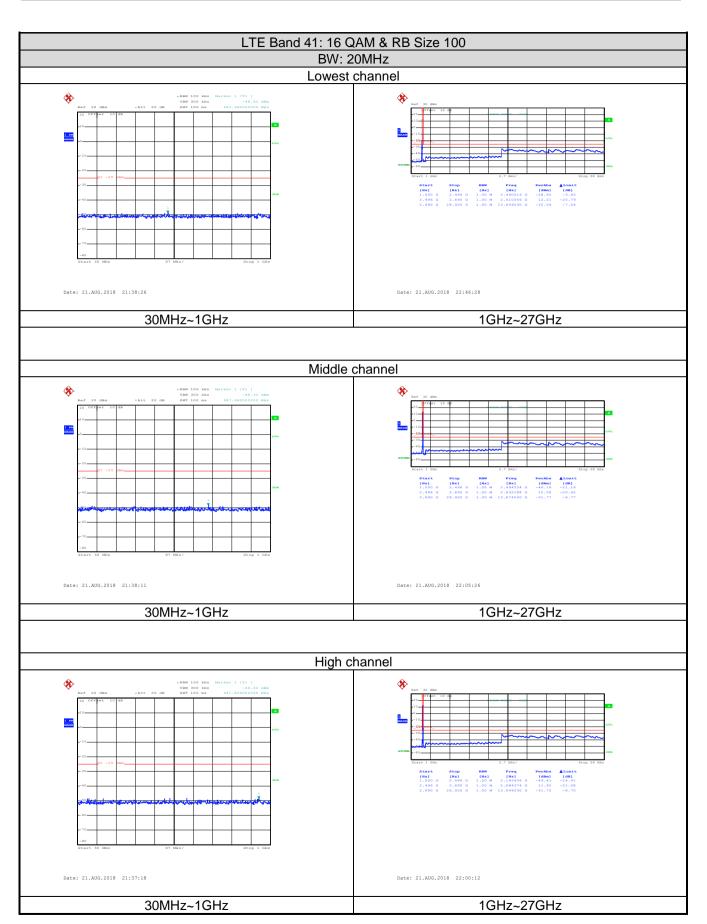






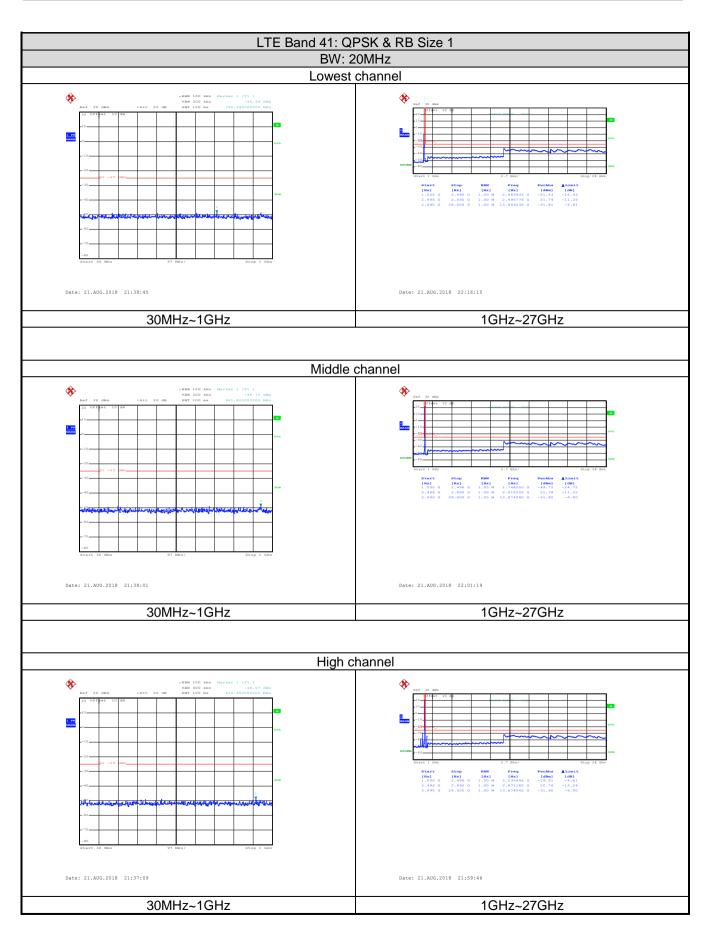






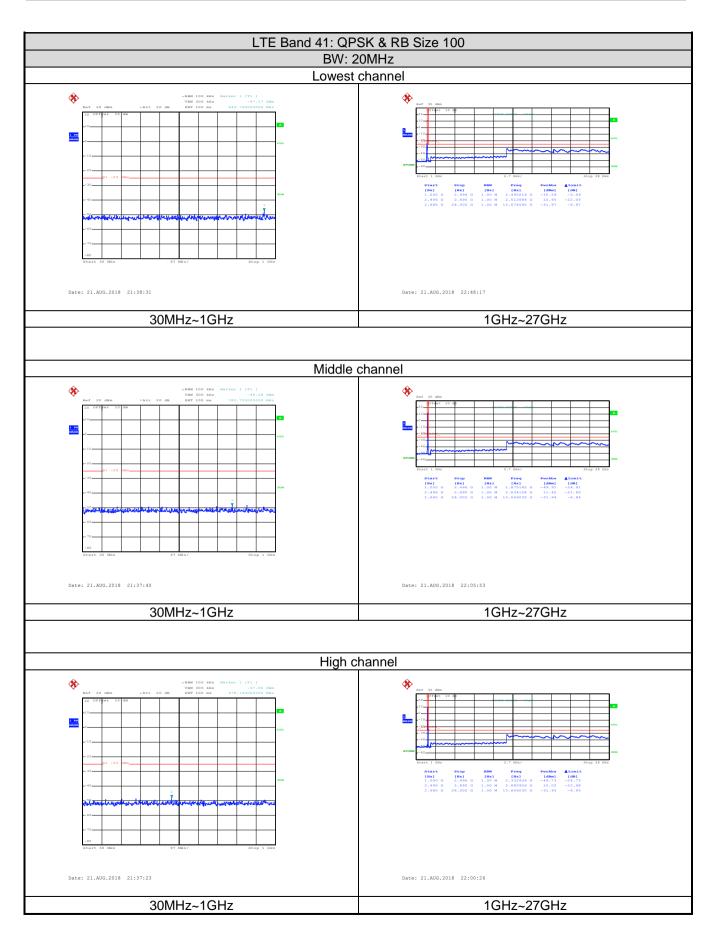






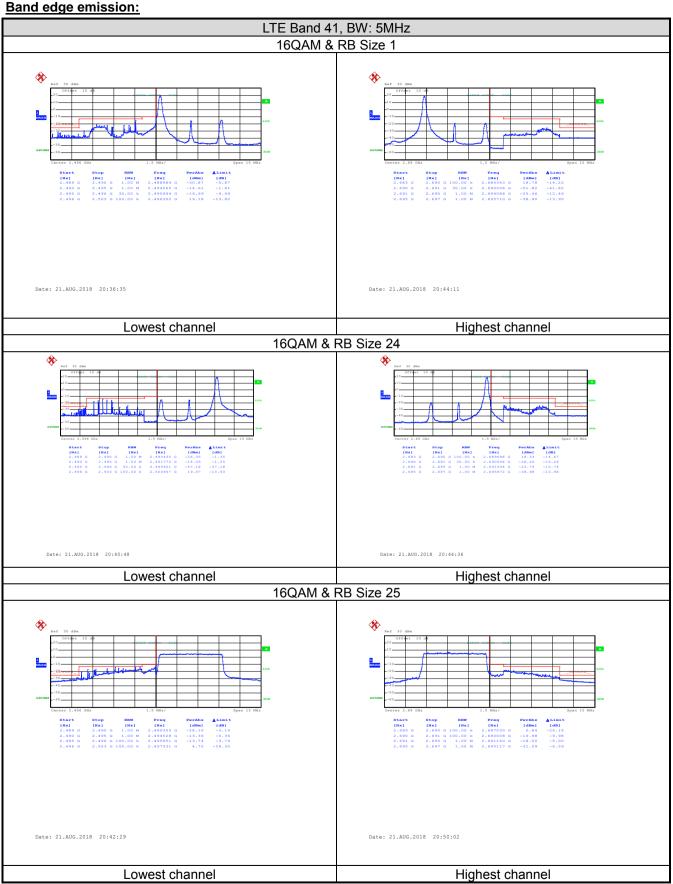




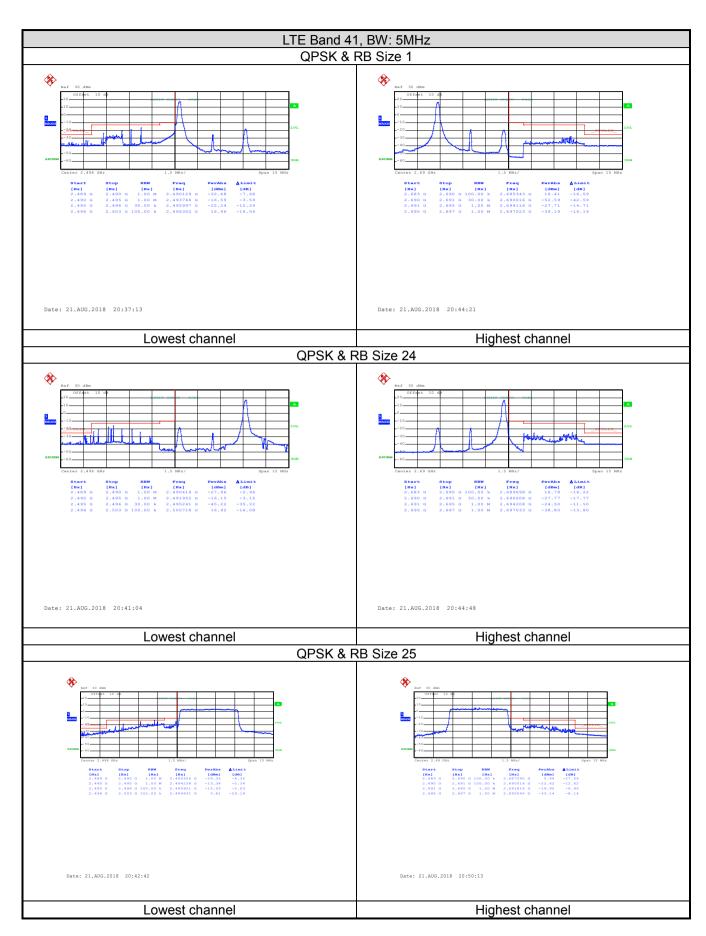




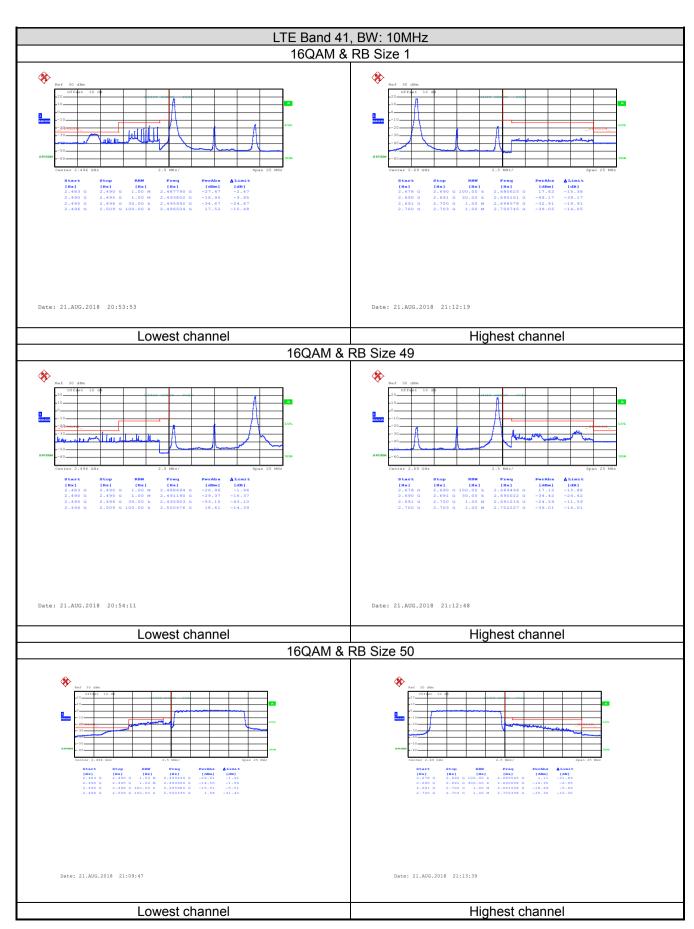




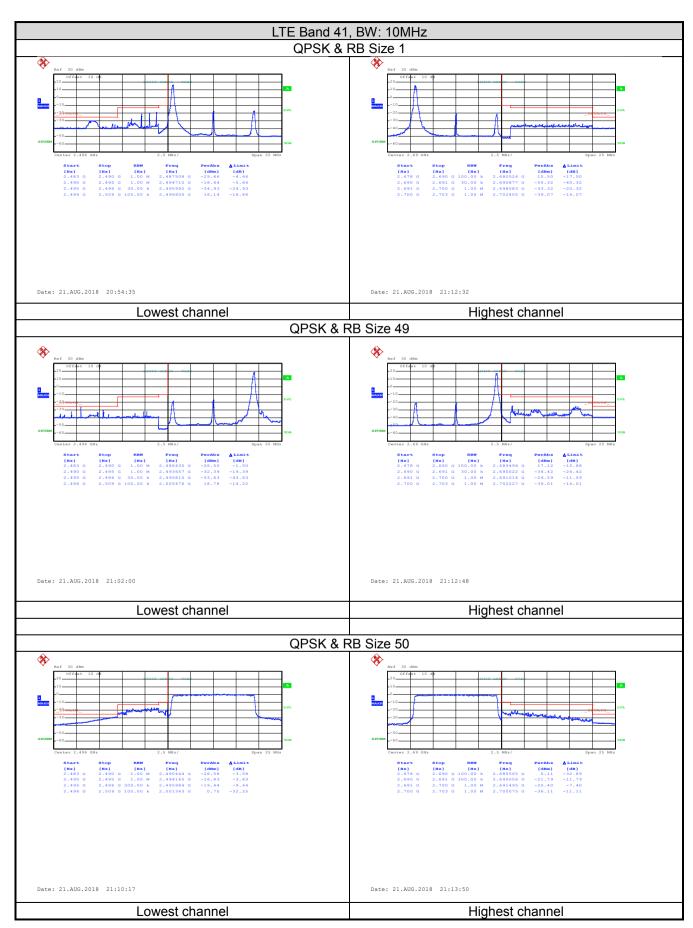




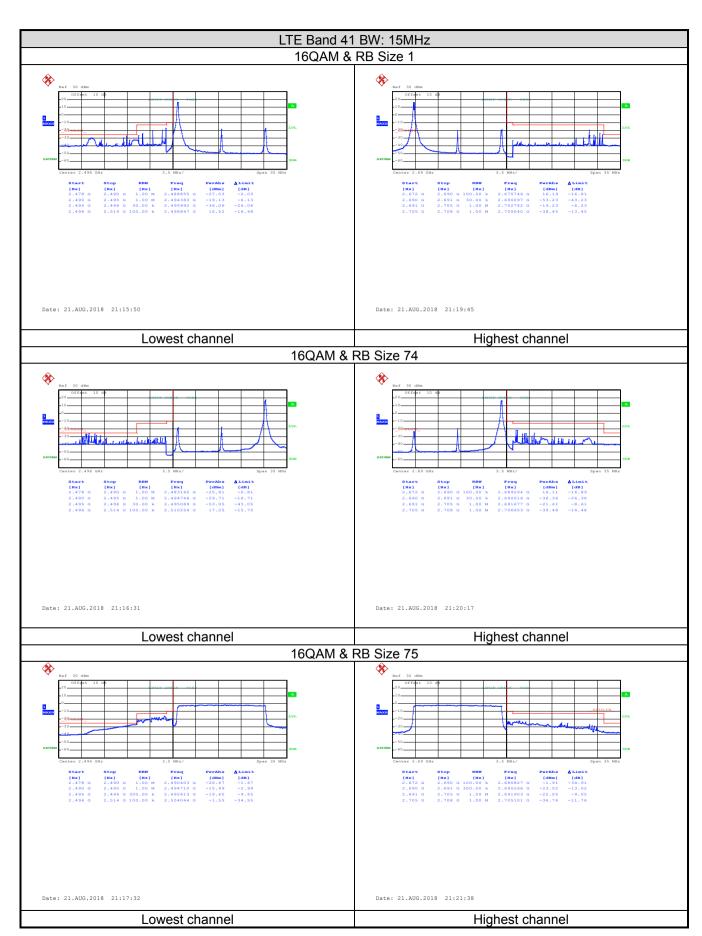






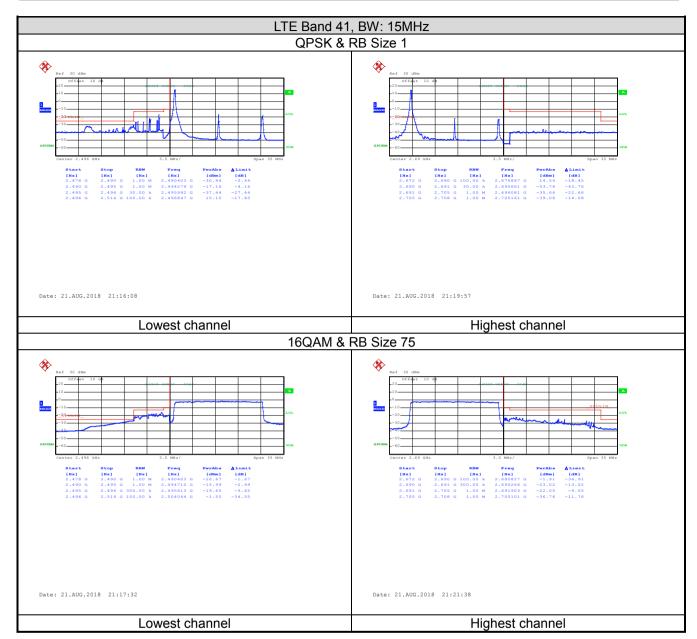






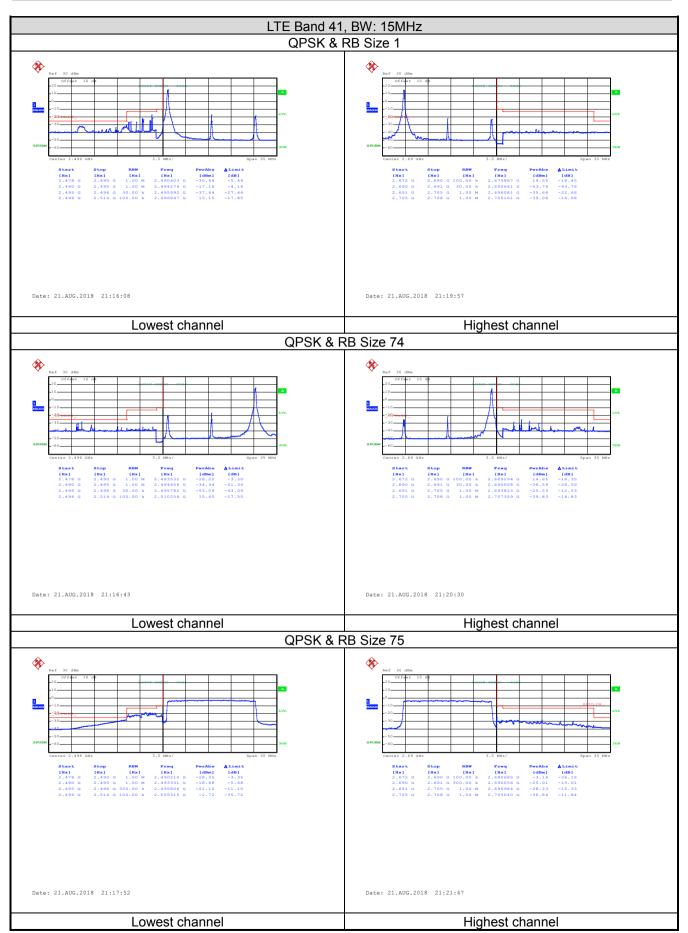






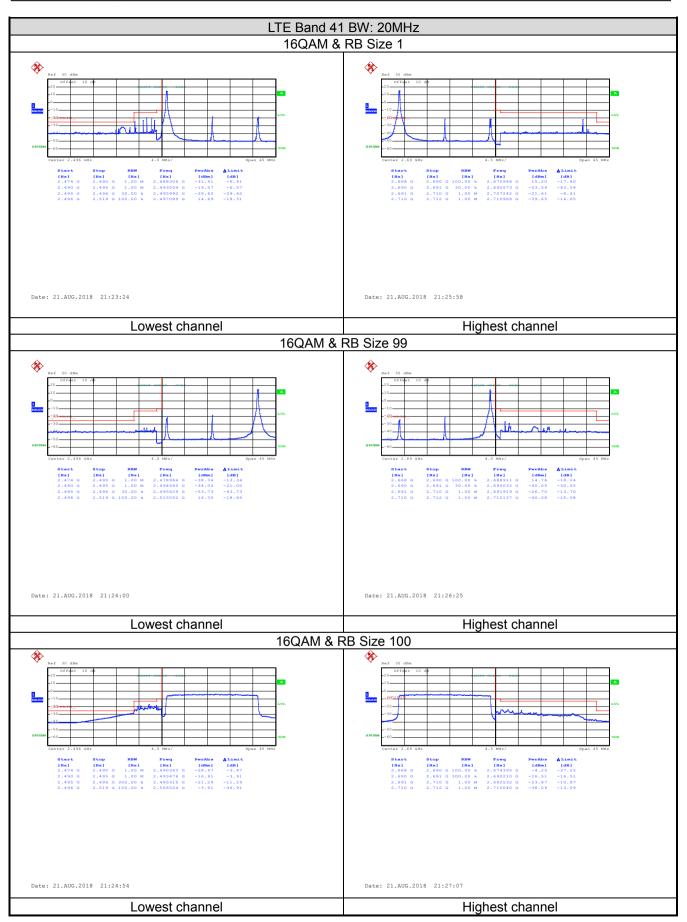






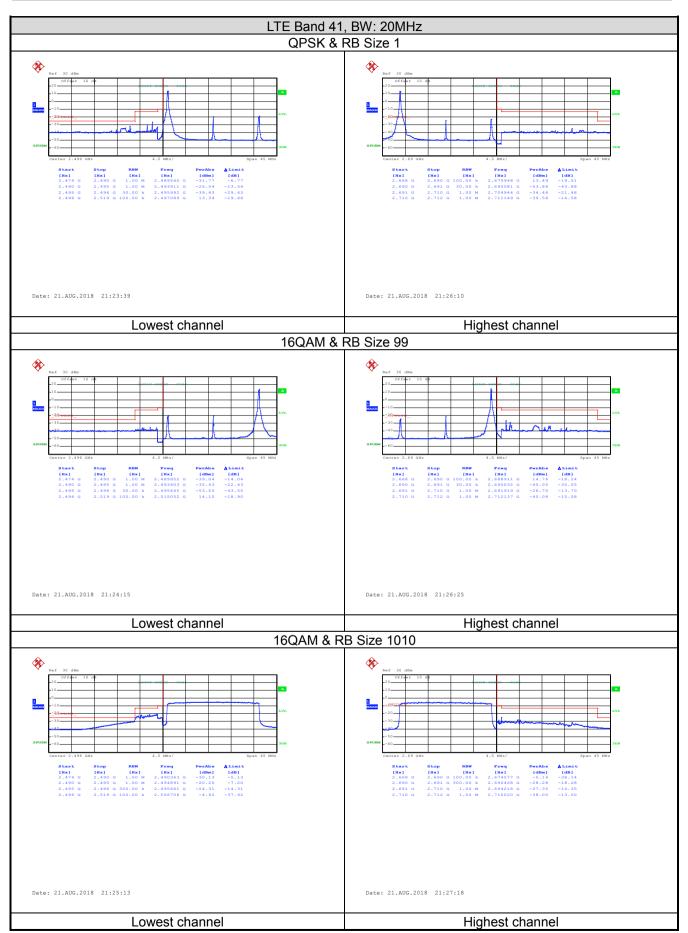














6.5 ERP, EIRP Measurement

0.5 ERP, EIRP Weasure	
Test Requirement:	Part 22.913(a)(2),Part 27.50 (h)
Test Method:	ANSI/TIA-603-D 2010
Limit:	Mobile and other user stations. Mobile stations are limited to 2.0 watts EIRP. All user stations are limited to 2.0 watts transmitter output power.
Test setup:	Antenna Tower Above 1GHz Antenna Tower Hom Antenna Tower
	Ground Reference Plane Test Receiver Amplier Controller
Test Procedure:	 The EUT was placed on an non-conductive turntable using a non-conductive support. The radiated emission at the fundamental frequency was measured at 3 m with a test antenna and EMI spectrum analyzer. During the measurement, the EUT was communication with the station. The highest emission was recorded with the rotation of the turntable and the lowering of the test antenna from 4m to 1m. The reading was recorded and the field strength (E in dBuV/m) was calculated. ERP in frequency band below 1GHz were measured using a substitution method. The EUT was replaced by dipole antenna connected, the S.G. output was recorded and ERP was calculated as follows: ERP = S.G. output (dBm) + Antenna Gain (dBd) - Cable Loss (dB) EIRP in frequency band above 1GHz were measured using a substitution method. The EUT was replaced by or horn antenna connected, the S.G. output was recorded and EIRP was calculated as follows: EIRP = S.G. output (dBm) + Antenna Gain (dBi) - Cable Loss (dB)
-	5. The worse case was relating to the conducted output power.
Test Instruments:	Refer to section 5.9 for details
Test mode:	Refer to section 5.3 for details
Test results:	Passed





Measurement Data

leasurement	Data							
			LTE Ba					
			BW: 5	MHz				
Frequency (MHz)	UL Channel	Modulation	EUT Pol.	Antenna Pol.	EIRP(dBm)	Limit (dBm)	Result	
			Lowest 0	Channel				
2498.50	39675	QPSK	Н	V	20.95			
2490.00	33073	QI SIX	11	Н	18.69	33.00	Pass	
2498.50	39675	16QAM	Н	V	20.93	33.00	1 433	
2490.00	33073	TOQAW	11	Н	18.47			
		_	Middle C	Channel	<u>, </u>			
2593.00	40620	QPSK	Н	V	21.02			
2333.00	40020	QI OIX	11	Н	18.95	33.00	Pass	
2593.00	40620	16QAM	Н	V	20.96	55.00	F 455	
2333.00	40020	TOQAW	11	Н	18.42			
			Highest (Channel				
2687.50	41565	QPSK	Н	V	20.63	33.00		
2007.00	71000	QI OIX	11	Н	18.25		Pass	
2687.50	2687.50 41565	16QAM	H V 20.11	33.00	1 400			
2007.50	71000	TOQAWI	11	Н	18.37			
		1	BW: 1	0MHz				
Frequency (MHz)	UL Channel	Modulation	EUT Pol.	Antenna Pol.	EIRP(dBm)	Limit (dBm)	Result	
			Lowest 0	Channel				
2501.00	39700	QPSK	Н	V	20.74			
2501.00	39700	QPSK	П	Н	18.36	33.00	Pass	
2501.00	4.00 20700 40041	501.00 39700	16QAM	Н	V	20.49	33.00	F 455
2501.00	39700	TOQAW	Π	Н	18.30			
			Middle C	Channel				
2593.00	40620	QPSK	Н	V	20.92			
2595.00	40020	QFSK	П	Н	18.24	33.00	Pass	
2593.00	40620	16QAM	Н	V	20.69	33.UU	F 455	
2030.00	40020	IUQAW	П	Н	18.32			
			Highest (Channel				
2685.00	41540	QPSK	Н	V	20.43			
2000.00	71040	QF UN	11	Н	18.39	33.00	Pass	
2685.00	41540	16QAM	Н	V	20.32	33.00	F 455	
2000.00	71040	IOQAW	''	Н	18.69			





			BW: 1	5MHz			
Frequency (MHz)	UL Channel	Modulation	EUT Pol.	Antenna Pol.	EIRP(dBm)	Limit (dBm)	Result
			Lowest C	Channel			
2502 50	20725	QPSK	Н	V	20.69		
2503.50	39725	QP5K	П	Н	18.52	33.00	Pass
2503.50	39725	16QAM	Н	V	20.62	33.00	Pass
2003.00	39723	TOQAM	П	Н	18.32		
			Middle C	Channel			
2593.00	40620	QPSK	Н	V	20.22		
2595.00	40020	QF3N	П	Н	18.58	33.00	Pass
2593.00	40620	16QAM	Н	V	20.01	33.00	F 455
2593.00	40620	TOWAIVI	П	Н	18.24		
			Highest (Channel			
2692.50	41515	QPSK	Н	V	20.24		
2682.50	41010	QP3N	П	Н	18.47	22.00	Door
2692 FO	44E4E	160414	Н	V	20.43	33.00	Pass
2682.50	41515	16QAM	П	Н	18.52		

	BW: 20MHz						
Frequency (MHz)	UL Channel	Modulation	EUT Pol.	Antenna Pol.	EIRP(dBm)	Limit (dBm)	Result
			Lowest C	Channel			
2506.00	39750	QPSK	Н	V	20.55		
2500.00	39730	QFSN	П	Н	18.95	33.00	Pass
2506.00	39750	16QAM	Н	V	20.24	33.00	Fd55
2506.00	39730	TOQAM	П	Н	18.33		
			Middle C	Channel			
2593.00	40620	QPSK	Н	V	20.41		
2393.00	40020	QFSK	11	Н	18.83	33.00	Pass
2593.00	40620	16QAM	Н	V	20.77	33.00	Fd55
2595.00	40020	TOQAM	11	Н	18.99		
			Highest (Channel			
2680.00	41490	QPSK	Н	V	20.83		
2080.00	41490	QFSN	П	Н	18.25	33.00	Pass
2680.00	41490	16QAM	Н	V	20.99	33.00	F 455
2000.00	41430	TOWAIN	П	Н	18.41		



6.6 Field strength of spurious radiation measurement

	Doub 22 047(b) Doub 27 52(m)
Test Requirement:	Part 22.917(b), Part 27.53(m)
Test Method:	ANSI/TIA-603-D 2010 For mobile digital stations, the attenuation factor shall be not less than 40
Limit:	+ 10 log (P) dB on all frequencies between the channel edge and 5 megahertz from the channel edge, 43 + 10 log (P) dB on all frequencies between 5 megahertz and X megahertz from the channel edge, and 55 + 10 log (P) dB on all frequencies more than X megahertz from the channel edge, where X is the greater of 6 megahertz or the actual emission bandwidth as defined in paragraph (m)(6) of this section. In addition, the attenuation factor shall not be less that 43 + 10 log (P) dB on all frequencies between 2490.5 MHz and 2496 MHz and 55 + 10 log (P) dB at or below 2490.5 MHz. Mobile Satellite Service licensees operating on frequencies below 2495 MHz may also submit a documented interference complaint against BRS licensees operating on channel BRS Channel 1 on the same terms and conditions as adjacent channel BRS or EBS licensees.
Test setup:	Below 1GHz
	Antenna Tower Test Receiver Test Receiver Anulise Another Controlles Above 1GHz
	Above IGHZ
	Hern Antenna Tower Ground Reference Plane Test Receiver Test Receiver Test Receiver
Test Procedure:	1. The EUT was placed on an non-conductive turntable using a non-
	conductive support. The radiated emission at the fundamental frequency was measured at 3 m with a test antenna and EMI spectrum analyzer. 2. During the tests, the antenna height and the EUT azimuth were varied in order to identify the maximum level of emissions from the EUT. This maximization process was repeated with the EUT positioned in each of its three orthogonal orientations. 3. The frequency range up to tenth harmonic was investigated for each
	of three fundamental frequency (low, middle and high channels). Once spurious emission was identified, the power of the emission

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	 was determined using the substitution method. 4. The spurious emissions attenuation was calculated as the difference between radiated power at the fundamental frequency and the spurious emissions frequency. ERP / EIRP = S.G. output (dBm) + Antenna Gain(dB/dBi) - Cable Loss (dB)
Test Instruments:	Refer to section 5.9 for details
Test mode:	Refer to section 5.3 for details.
Test results:	Passed

Measurement Data:

	LT	E Band 41, WB: 5MH	z			
	RB size	e 1 & RB offset 0 for	QPSK			
Fraguenov (MHz)	Spurious	Emission	Limit (dPm)	Result		
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result		
		Lowest Channel				
4997.00	Vertical	-41.96				
7495.50	V	-34.42				
9994.00	V	-31.03	-25.00	Pass		
4997.00	Horizontal	-42.71	-25.00	Pass		
7495.50	Н	-34.91				
9994.00	Н	-32.62				
		Middle Channel				
5186.00	Vertical	-41.55				
7779.00	V	-34.53				
10372.00	V	-33.03	25.00	Door		
5186.00	Horizontal	-41.68	-25.00	Pass		
7779.00	Н	-34.64				
10372.00	Н	-32.75				
		Highest Channel				
5375.00	Vertical	-40.72				
8062.50	V	-33.57				
10750.00	V	-31.64	25.00	Door		
5375.00	Horizontal	-40.16	-25.00	Pass		
8062.50	Н	-34.33	1			
10750.00	Н	-30.24				

Note:

^{1.} The emission levels of below 1 GHz are 20 dB lower than the limit so not show in this report.

^{2.} For above 1 GHz, all test modes were performed, and just the worst case shown in the report.





	LTI	E Band 41, WB: 10MF	-lz			
	RB size	1 & RB offset 0 for	QPSK			
Erogueney (MHz)	Spurious	Emission	Limit (dRm)	Result		
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result		
		Lowest Channel				
5002.00	Vertical	-41.83				
7503.00	V	-34.81				
10004.00	V	-31.45	-25.00	Pass		
5002.00	Horizontal	-42.31	-25.00	Pass		
7503.00	Н	-34.51				
10004.00	Н	-32.54				
		Middle Channel				
5186.00	Vertical	-41.46				
7779.00	V	-34.16				
10372.00	V	-33.76	-25.00	Pass		
5186.00	Horizontal	-41.83	-25.00	Pass		
7779.00	Н	-34.52				
10372.00	Н	-32.75				
		Highest Channel				
5370.00	Vertical	-40.71				
8055.00	V	-33.33				
10740.00	V	-31.24	-25.00	Pass		
5370.00	Horizontal	-40.49	-25.00	Pass		
8055.00	Н	-34.93	_			
10740.00	Н	-30.25				

Note:

^{1.} The emission levels of below 1 GHz are 20 dB lower than the limit so not show in this report.

^{2.} For above 1 GHz, all test modes were performed, and just the worst case shown in the report.





	LT	E Band 41, WB: 15MI	Hz			
	RB siz	e 1 & RB offset 0 for	QPSK			
Fraguenov (MHz)	Spurious	Emission	Limit (dPm)	Result		
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result		
		Lowest Channel				
5007.00	Vertical	-41.53				
7510.50	V	-34.50				
10014.00	V	-31.55	-25.00	Pass		
5007.00	Horizontal	-42.12	-25.00	Pass		
7510.50	Н	-34.24				
10014.00	Н	-32.45				
		Middle Channel				
5186.00	Vertical	-41.77				
7779.00	V	-34.46				
10372.00	V	-33.51	-25.00	Pass		
5186.00	Horizontal	-41.75	-25.00	F455		
7779.00	Н	-34.75				
10372.00	Н	-32.41				
		Highest Channel				
5365.00	Vertical	-40.83				
8047.50	V	-34.00				
10730.00	V	-31.66	-25.00	Pass		
5365.00	Horizontal	-40.95	-25.00	Fd55		
8047.50	Н	-34.17				
10730.00	Н	-30.42				

Note:

^{1.} The emission levels of below 1 GHz are 20 dB lower than the limit so not show in this report.

^{2.} For above 1 GHz, all test modes were performed, and just the worst case shown in the report.





	LT	E Band 41, WB: 20MI	Hz			
	RB size	1 & RB offset 0 for	QPSK			
Frequency (MHz)	Spurious	Emission	Limit (dPm)	Result		
Frequency (MHZ)	Polarization	Level (dBm)	Limit (dBm)	Result		
		Lowest Channel				
5012.00	Vertical	-41.53				
7518.00	V	-34.80				
10024.00	V	-31.10	-25.00	Pass		
5012.00	Horizontal	-42.37	-25.00	Fa55		
7518.00	Н	-34.08				
10024.00	Н	-32.07				
		Middle Channel				
5186.00	Vertical	-41.79				
7779.00	V	-34.83				
10372.00	V	-33.75	25.00	Door		
5186.00	Horizontal	-41.95	-25.00 Pass			
7779.00	Н	-34.39				
10372.00	Н	-32.50				
		Highest Channel				
5360.00	Vertical	-40.54				
8040.00	V	-33.55				
10720.00	V	-31.81	-25.00	Pass		
5360.00	Horizontal	-40.08	-25.00	Pass		
8040.00	Н	-34.14				
10720.00	Н	-30.52				

Note:

^{1.} The emission levels of below 1 GHz are 20 dB lower than the limit so not show in this report.

^{2.} For above 1 GHz, all test modes were performed, and just the worst case shown in the report.





6.7 Frequency stability V.S. Temperature measurement

Test Requirement:	Part 27.54, Part 2.1055(a)(1)(b)
Test Method:	ANSI/TIA-603-D 2010
Limit:	±2.5ppm
Test setup:	SS BUT Divider Temperature & Humidity Chamber Power Source
Test procedure:	 The equipment under test was connected to an external DC power supply and input rated voltage. RF output was connected to a frequency counter or spectrum analyzer via feed through attenuators. The EUT was placed inside the temperature chamber. Set the spectrum analyzer RBW low enough to obtain the desired frequency resolution and measure EUT 25°C operating frequency as reference frequency. Turn EUT off and set the chamber temperature to -30°C. After the temperature stabilized for approximately 30 minutes recorded the frequency. Repeat step measure with 10°C increased per stage until the highest temperature of +50°C reached
Test Instruments:	Refer to section 5.9 for details
Test mode:	Refer to section 5.3 for details
Test results:	Passed





Measurement Data (worst case):

Reference Fr	equency: LTE Band 4	1 (10MHz) Mide	dle channel=4062	0 channel=2593.0	00MHz
Power supplied	Temperature (°C)	Frequency error		Limit (ppm)	Result
(Vdc)	Temperature (C)	Hz	ppm	Limit (ppm)	Nesuit
		QPSK			
	-30	199	0.105851		
	-20	156	0.082979		
	-10	164	0.087234		
	0	124	0.065957		
3.70	10	189	0.100532	±2.5	Pass
	20	175	0.093085		
	30	115	0.061170	-	
	40	106	0.056383		
	50	151	0.080319		
		16QAM			
	-30	124	0.065957		
	-20	151	0.080319		
	-10	167	0.088830		
	0	123	0.065426		
3.70	10	145	0.077128	±2.5	Pass
	20	141	0.075000		
	30	157	0.083511	1	
	40	134	0.071277		
	50	139	0.073936	1	





6.8 Frequency stability V.S. Voltage measurement

Test Requirement:	Part 27.54, Part 2.1055(d)(2)			
Test Method:	ANSI/TIA-603-D 2010			
Limit:	±2.5ppm			
Test setup:	SS EUT Divider Temperature & Humidity Chamber			
Test procedure:	 Set chamber temperature to 25°C. Use a variable DC power source to power the EUT and set the voltage to rated voltage. Set the spectrum analyzer RBW low enough to obtain the desired frequency resolution and recorded the frequency. Reduce the input voltage to specify extreme voltage variation (+/-15%) and endpoint, record the maximum frequency change. 			
Test Instruments:	Refer to section 5.9 for details			
Test mode:	Refer to section 5.3 for details			
Test results:	Passed			



Measurement Data (worst case):

LTE Band 41 part:

	equency: LTE Band 4	·			
Temperature ($^{\circ}$)	Power supplied	Frequency error		Limit (ppm)	Result
	(Vdc)	Hz	ppm	Еши (ррш)	Nesuit
		QPSK			
25	4.25	99	0.052660	±2.5	Pass
	3.70	66	0.035106		
	3.50	75	0.039894		
		16QAM			
25	4.25	81	0.043085	±2.5	Pass
	3.70	97	0.051596		
	3.50	49	0.026064		

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